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INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ/T 2658.6-2015

Replacing SJ/T 2658.6-1986

Measuring method for semiconductor infrared-emitting diode. Part 6: Radiant power

半导体红外发射二极管测量方法 第6部分：辐射功率

(English Translation)

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What this standard covers

This standard specifies the measurement principle, measurement procedures and specified conditions for the radiation power of semiconductor infrared emission diodes (hereinafter referred to as devices). This standard applies to semiconductor infrared emitting diodes.

Document data

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Standards quoted by this document

GB/T 2900.65-2004; SJ/T 2658.1

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